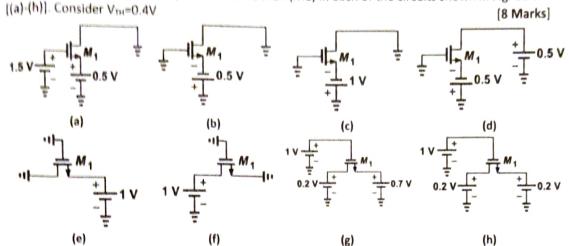
Quiz-2: Analog Electronic Circuits (S25.EC2.103)

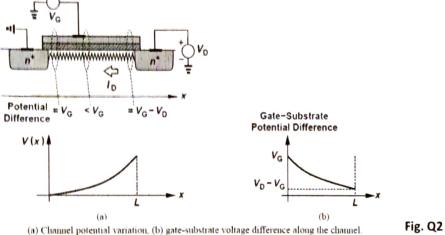
NOTE: No query allowed during the exam. Write your assumptions (if any) for each question.

 ${f Q1}.$ Determine the region of operation of MOSFET (M1) in each of the circuits shown in Fig. below.



Q2. Referring to Fig. Q2 below and assume $V_D > 0$,

[5 Marks]



- (a) Sketch the electron density in the channel as a function of x.
- (b) Sketch the local resistance of the channel (per unit length) as function of x.

Q3 (a). What is the effect of temperature on MOSFET. Discuss through the basic MOS equation, e.g. how your ID get effected with rise in temperature when the MOSFET is in Saturation? [2 Marks]

(b). Pick the right option [(I)-(IV)]

[4 Marks]

- (I). The capacitances in MOSFET occurs due to _
 - i. Interconnects
 - Difference in Doping concentration ii.
 - Difference in dopant materials iii.
 - All of the mentioned iv.
- (II). The parasitic capacitances found in MOSFET are
 - Oxide related capacitances i.
 - ii. Inter electrode capacitance

- iii. Electrolytic capacitance
- iv. All of the mentioned

(III). In Cut-off region (assume MOS is in accumulation), the capacitance Cgs will be equal to

- i. 2C_{GD0}
- ii. Coso.W
- iii. CGB
- iv. All of the mentioned

(IV). In saturation mode operation, gate to drain capacitance (channel) is considered zero due to_____

- i. Gate and drain are interconnected
- ii. Channel length is reduced
- iii. Inversion layer doesn't exist
- iv. Drain is connected to ground

Q4. In the Fig.Q4, what is the minimum allowable value of V_{DD} if M1 must not enter the triode region?

Assume $\lambda=0$, $V_{TH}=0.4V$, $\mu_n C_{ox}=200 \mu A/V^2$

[5 Marks]

$$R_{D} \ge 500 \Omega$$

$$1 \lor \frac{1}{1} = \frac{10}{0.18}$$

Fig. Q4

Q5. Sketch I_X as a function of V_X for the circuits shown in Fig. Q5. Assume V_X goes from 0 to VDD=1.8V. Determine at what value of V_X the device changes its region of operation. Consider λ =0, V_{TH} = 0.4V. [6 Marks]

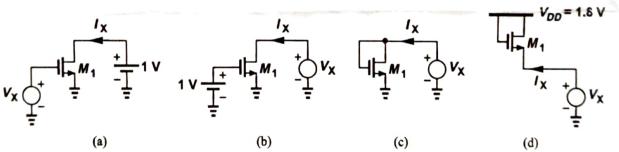


Fig. Q5